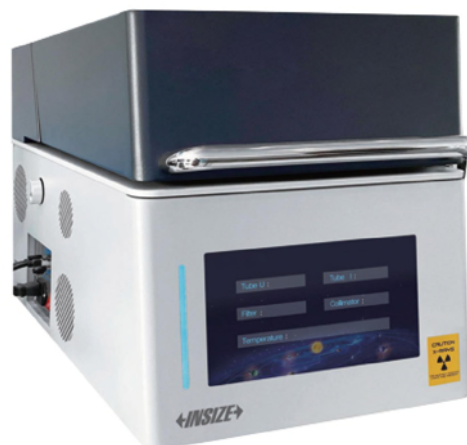


VACUUM XRF PLATING THICKNESS INSTRUMENT/ROHS ANALYZER PART NO. XRF-VF300-U

VACUUM SYSTEM
MANUAL ZOOM

- According to DIN ISO 3497, DIN 50987, and ASTM B568
- Used for RoHS analysis, electroplating/electrophoretic plating analysis
- Minimum measurement area of .00031in² with micro-focus X-ray generator and advanced optical switching focusing system
- Equipped with manual zoom technology, it allows for non-destructive testing of irregular components with depths from 0 to 1.18"
- Core EFP algorithm for simultaneous analysis of 23 plating layers, 24 elements
- Equipped with an intelligent vacuum system, it enhances the precision of analysis for platings of light elements, resulting in more stable data



SPECIFICATION

RoHS analysis	range of elemental analysis	Cd, Pb, Hg, Br, Cr, Cl, As, Sb
	detection limit	2ppm
	content range	2ppm~99%
Plating analysis	range of elemental analysis	Li (3)-U (92)
	detection limit	.197μin
	range of plating thickness	.394~3149.6μin
Algorithm		EFP
Analysis time		5~300s
Detector		SDD (silicon drift detector)
X-ray device		microfocus enhanced ray tube
Collimator		automatic switching of 4 types of collimators: .020"DIA, .059"DIA, .118"DIA, .315"DIA
Spot spread at the nearest measurement distance		<10%
Sample observation		1/2.7" color CCD with zoom functionality
Distance to zoom		0~1.18"
Focusing method		highly sensitive lenses with manual focusing
Vacuum system		intelligent vacuum system
Height of vacuum cavity		3.15"
Working environment		59~86°F, <70%RH
Power supply		AC110V, 60Hz, 95W
Dimension (W×D×H)		21.65×16.14×14.57"
Weight		110.2lb

STANDARD DELIVERY

Main unit	1 pc
Computer	1 set
Software	1 set
Printer	1 pc
Vacuum pump	1 pc
Accessory case	1 pc
12 elemental tablet	1 set
Ni standard sheet	1 pc
Ag standard sheet	1 pc
ERM-EC681m standard sheet	1 pc

OPTIONAL ACCESSORY

Plating solution measuring cup	XRF-PT230-MC
Solution test membrane	XRF-PT230-SF
Au standard sheet	MSS-P01
Cr standard sheet	MSS-P02
Cu standard sheet	MSS-P03
Zn standard sheet	MSS-P04